

<b>Notice of References Cited</b>	Application/Control No. 10/736,342	Applicant(s)/Patent Under Reexamination SHUKLA ET AL.	
	Examiner Sow-Fun Hon	Art Unit 1772	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,963,290	10-1999	Murai et al.	349/191
	B	US-6,028,124	02-2000	Glover et al.	522/181
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Periodic Table undated [retrieved on 12/06/04] Retrieved from the internet: < <a href="http://www.swansontec.com/selement.htm">http://www.swansontec.com/selement.htm</a> >
	V	Joseph Lauher, Acid and Base Strengths, Spring 2002 [retrieved on 12/08/04] Retrieved from the internet < <a href="http://66.218.71.225/search/cache?p=pk+acl&amp;toggle=1&amp;ei=UTF-8&amp;u=www.lauher.com/che142/acidbase.pdf&amp;w=pk+acl&amp;d=84A083EAE8&amp;icp=1&amp;.intl=us">http://66.218.71.225/search/cache?p=pk+acl&amp;toggle=1&amp;ei=UTF-8&amp;u=www.lauher.com/che142/acidbase.pdf&amp;w=pk+acl&amp;d=84A083EAE8&amp;icp=1&amp;.intl=us</a> >
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.